## JAN 3 1 2006

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.:10/695,336

Applicant(s): Geiss et al.

Filed.: October 28, 2003

Art Unit: 2813

Dkt. No.: BUR920010184US2

Examiner: Heather Anne Doty

Title: METHOD OF CONTROLLING GRAIN SIZE IN A POLYSILICON LAYER AND

IN SEMICONDUCTOR DEVICES HAVING POLYSILICON STRUCTURES

## PETITION UNDER 35 USC 1.136(a)

Commissioner for Patents & Trademarks P. O. Box 1450 Alexandria, VA 22313-1450

Applicants hereby petition for a two month extension of time for responding to the final office action of September 14, 2005. The Director is hereby authorized to charge Deposit Account 09-0456 for the fee required under 35 USC 1.17(a).

Respectfully submitted, FOR: Geiss et al.

Dated: 01/31/2006

Jack P. Friedman Reg. No. 44,688

FOR:

Anthony M. Palagonia Registration No.: 41,237

3 Lear Jet Lane, Suite 201 Schmeiser, Olsen & Watts Latham, New York 12110 (518) 220-1850

Agent Direct Dial Number: (802)-899-5460